

Image Processing: Machine Vision Applications II

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Editors

**20–22 January 2009
San Jose, California, USA**

Sponsored and Published by
IS&T—The Society for Imaging Science and Technology
SPIE

Volume 7251

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Author(s), "Title of Paper," in *Image Processing: Machine Vision Applications II*, edited by Kurt S. Niel, David Fofi, Proceedings of SPIE-IS&T Electronic Imaging, SPIE Vol. 7251, Article CID Number (2009).

ISSN 0277-786X

ISBN 9780819475015

Copublished by

SPIE

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Printed in the United States of America.

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